

<b>Notice of References Cited</b>	Application/Control No. 10/635,649	Applicant(s)/Patent Under Reexamination HATADE ET AL.	
	Examiner VAN T. PHAM	Art Unit 2627	Page 1 of 1

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*	A	US-6,728,193	04-2004	Uchizaki et al.	369/112.01
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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